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C AN EXAMPLE ERROR ON THE PUBLIC MODULUS OF THE WIDEVINE TRUSTLET

Original N :

0xc44dc735f6682a261a0b8545a62dd13df4c646a5ede482cef858925baa1811fa
 0284766b3d1d2b4d6893df4d9c045efe3e84d8c5d03631b25420f1231d8211e23
 22eb7eb524da6c1e8fb4c3ae4a8f5ca13d1e0591f5c64e8e711b3726215cec59ed
 0ebc6bb042b917d44528887915fdf764df691d183e16f31ba1ed94c84b476e74b
 488463e85551022021763af35a64ddf105c1530ef3fcf7e54233e5d3a4747bbb17
 328a63e6e3384ac25ee80054bd566855e2eb59a2fd168d3643e44851acf0d118f
 b03c73ebc099b4add59c39367d6c91f498d8d607af2e57cc73e3b5718435a8112
 3f080267726a2a9c1cc94b9c6bb6817427b85d8c670f9a53a777511b **Corrupted**
 N_{in} :

0x...8cb3...

Factors of corrupted N_{in} :

0x11, 0x033b, 0x377, 0x010819f1285c6b307a82beba93d7c496488...

Private key d_m :

0x062cde999954a9ced6840f2b04ae4d4187baa01a5044c0242c70dbe...

A FAULTS INDUCED BY A HIGH VOLTAGE

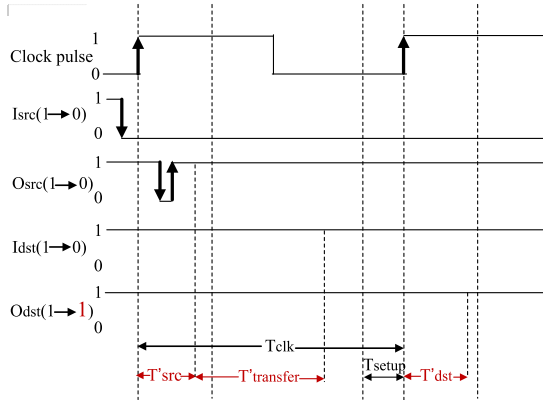


Figure 11: The bit-flip will be inserted if E_{src} becomes unstable because of a high voltage.

B THE IMPLEMENTATION OF FUNCTION ENDIANINVERSION IN ALGORITHM 1

Algorithm 2 The endian reversal algorithm

Input: The variable that needs to be endian reversed, V

Output: The reversed bytes sequence, S

```

1: function ENDIANINVERSION( $V$ )
2:    $S \leftarrow \{0\}$ 
3:   for each  $i \in [0, \text{bytelen}(V)/4 - 1]$  do
4:      $S_{temp} \leftarrow V[i * 4] \ll 24$ 
5:      $S_{temp} \leftarrow (V[i * 4 + 1] \ll 8) | S_{temp}$ 
6:      $S_{temp} \leftarrow (V[i * 4 + 2] \gg 8) | S_{temp}$ 
7:      $S_{temp} \leftarrow (V[i * 4 + 3] \gg 24) | S_{temp}$ 
8:      $Index \leftarrow \text{bytelen}(V) - (i + 1) * 4$ 
9:      $S[Index, Index + 3] \leftarrow S_{temp}$ 
10:  end for
11:  return  $S$ 
12: end function
    
```